

<b>Notice of References Cited</b>	Application/Control No. 10/042,829	Applicant(s)/Patent Under Reexamination CHENG ET AL.	
	Examiner Kiley Stoner	Art Unit 1725	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,655,704	08-1997	Sakemi et al.	228/246
	B	US-6,182,356	02-2001	Bolde, Lannie R.	29/821
	C	US-6,413,850	07-2002	Ooroku et al.	438/613
	D	US-6,270,002	08-2001	Hayashi et al.	228/246
	E	US-6,390,351	05-2002	Kasai et al.	228/41
	F	US-6,253,992	07-2001	Fjelstad, Joseph	228/245
	G	US-6,268,275	07-2001	Cobbley et al.	438/612
	H	US-6,551,917	04-2003	Cobbley et al.	438/613
	I	US-5,839,641	11-1998	Teng, Kun-Tang	228/41
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP-0902610A1	03-1999	EP	Tondelli et al.	
	O	JP-408139440A	05-1996	JP	Kin	
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	US 2002/0139730A1 Itou et al. (10-3-02).
	V	US 2002/0058406A1 Mukuno et al. (5-16-02).
	W	US 2001/0041437A1 Cobbley et al. (11-15-01).
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.